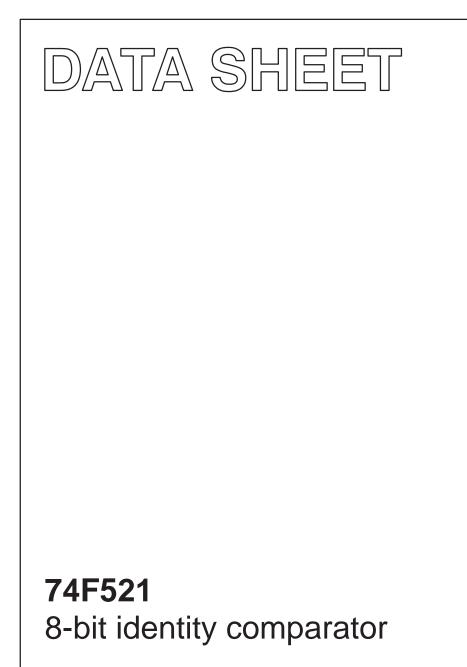
INTEGRATED CIRCUITS



Product specification

1990 May 15

IC15 Data Handbook



PHILIPS

Semiconductors

Philips

74F521

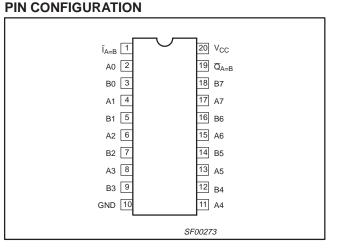
FEATURES

- Compares two 8-bit words in 6.5ns typical
- Expandable to any word length

DESCRIPTION

The 74F521 is an expandable 8-bit comparator. It compares two words of up to 8 bits each and provides a Low output when the two words match bit for bit. The expansion input $\overline{I}_{A=B}$ also serves as an active-Low enable input.

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F521	7.0ns	24mA



ORDERING INFORMATION

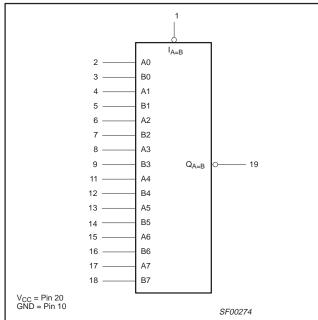
DESCRIPTION	COMMERCIAL RANGE V _{CC} = 5V ±10%, T _{amb} = 0°C to +70°C	PKG DWG #
20-pin plastic DIP	N74F521N	SOT146-1
20-pin plastic SOL	N74F521D	SOT163-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

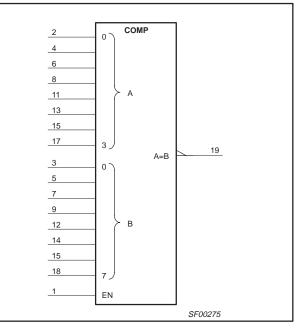
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A0 – A7	Word A inputs	1.0/1.0	20µA/0.6mA
B0 – B7	Word B inputs	1.0/1.0	20µA/0.6mA
Ī _{A=B}	Expansion or Enable input (active Low)	1.0/1.0	20µA/0.6mA
Q _{A=B}	Identity output (active Low)	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL



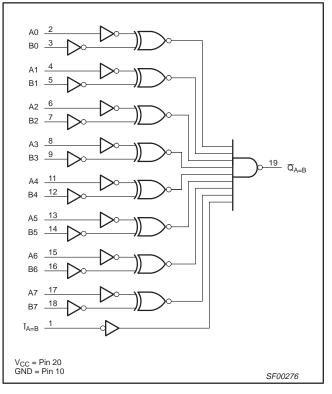
IEC/IEEE SYMBOL



Downloaded from Elcodis.com electronic components distributor

74F521

LOGIC DIAGRAM



FUNCTION TABLE

INP	INPUTS					
Ī _{A=B}	А, В	Q _{A=B}				
L	A=B*	L				
L	A≠B	Н				
н	A=B*	н				
н	A≠B	н				

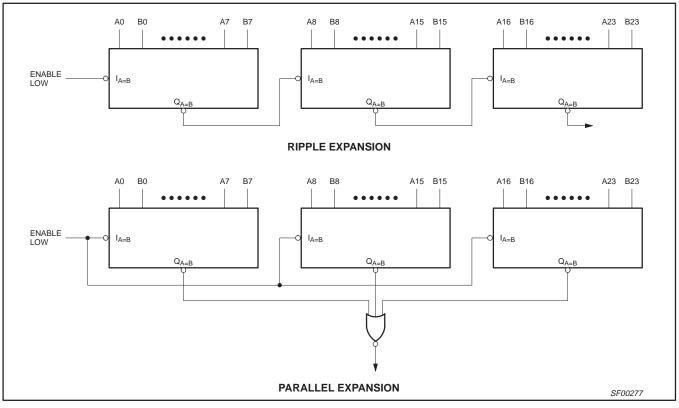
H = High voltage level

L = Low voltage level

X = Don't care

* A0=B0, A1=B1, A2=B2, etc.

APPLICATIONS



74F521

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	–0.5 to V_{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	DADAMETED		UNIT		
STMBOL	PARAMETER	MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-1	mA
I _{OL}	Low-level output current			20	mA
T _{amb}	Operating free-air temperature range	0		+70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIC		LIMITS		UNIT	
STWIDUL	FARAINETER			MIN	TYP ²	MAX	UNIT	
V			$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}	2.5			V
V _{OH}	High-level output voltage		$V_{IH} = MIN, I_{OH} = MAX$	±5%V _{CC}	2.7	3.4		V
M			$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}		0.30	0.50	V
V _{OL}	Low-level output voltage	$V_{IH} = MIN, I_{OL} = MAX$	±5%V _{CC}		0.30	0.50	V	
V _{IK}	Input clamp voltage		$V_{CC} = MIN, \ I_I = I_{IK}$			-0.73	-1.2	V
I	Input current at maximum input v	oltage	$V_{CC} = MAX, V_I = 7.0V$				100	μΑ
I _{IH}	High-level input current		$V_{CC} = MAX, V_I = 2.7V$				20	μΑ
IIL	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$				-0.6	mA
I _{OS}	Short-circuit output current ³		V _{CC} = MAX		-60		-150	mA
1	Supply current (total)					24	36	mA
ICC			$V_{CC} = MAX$			24	36	mA

NOTES:

 For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting the base of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting the base of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting the base of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting the base of high-speed test apparatus and/or sample-and-hold techniques. of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

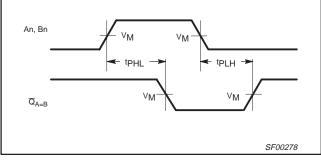
74F521

AC ELECTRICAL CHARACTERISTICS

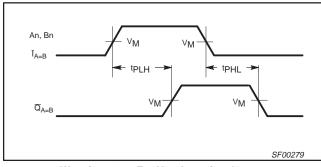
					LIM	ITS		
SYMBOL	PARAMETER	TEST CONDITION	T _a	_{CC} = +5.0 _{mb} = +25 0pF, R _L =	°C		0V ± 10% C to +70°C R _L = 500Ω	UNIT
			MIN	ТҮР	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay An or Bn to $\overline{Q}_{A=B}$	Waveform 1, 2	3.5 3.0	8.0 8.0	9.5 9.0	3.5 2.5	11.0 10.5	ns
t _{PLH} t _{PHL}	Propagation delay $I_{A=B}$ to $\overline{Q}_{A=B}$	Waveform 2	3.0 3.5	5.0 6.5	6.5 7.0	3.0 3.5	7.5 8.0	ns

AC WAVEFORMS

For all waveforms, $V_M = 1.5V$.

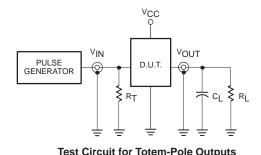


Waveform 1. For Inverting Outputs



Waveform 2. For Non-Inverting Outputs

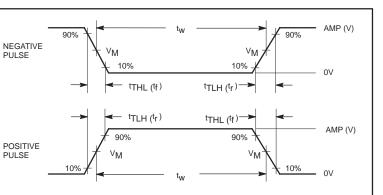
TEST CIRCUIT AND WAVEFORMS



Test Circuit for Totem-Pole Outputs

DEFINITIONS:

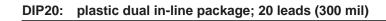
- R_L = Load resistor;
- see AC ELECTRICAL CHARACTERISTICS for value. Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value. $C_L =$ Termination resistance should be equal to ZOUT of RT =
- pulse generators.

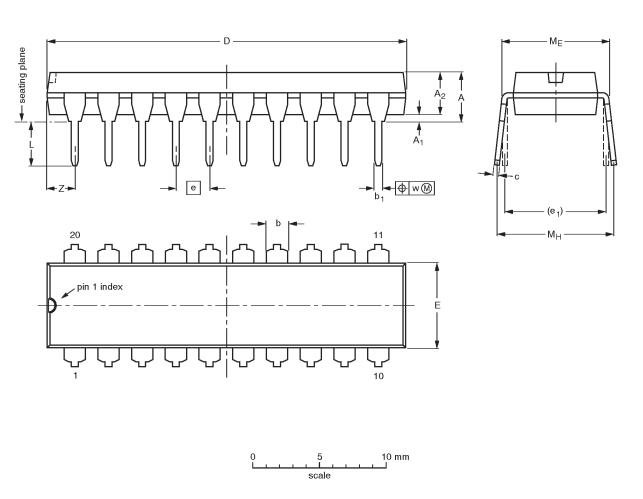


Input Pulse Definition

family	INPUT PULSE REQUIREMENTS								
family	amplitude	tude V _M rep. rate t _w		t _{TLH}	t _{THL}				
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns			

SF00006





DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	c	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	M _E	M _H	v	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.0
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

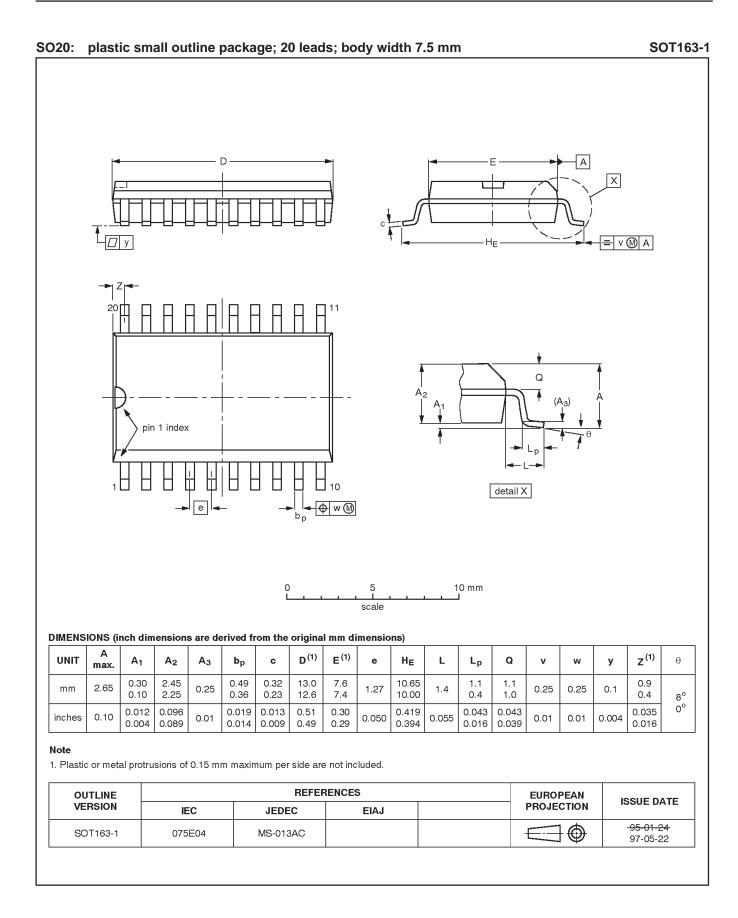
Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT146-1			SC603			-92-11-17- 95-05-24

74F521

74F521



74F521

Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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